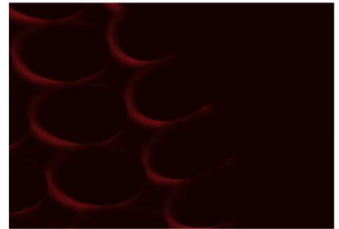
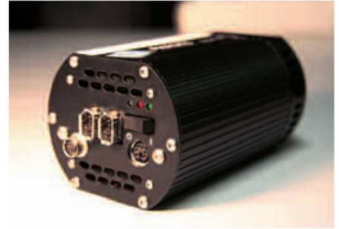
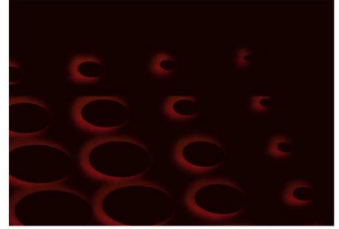
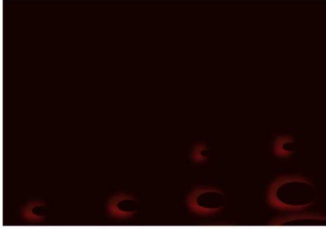


SID4



SID4



▼ KEY FEATURES

- High transverse resolution (160x120)
- Achromaticity
- Large spectral acceptance
- Intensity profile characterization (BeamView)
- Compact and versatile (controlled by laptop, "plug'n play")
- Multi-user, multi-device interface
- Easy to implement and user friendly software
- Various acquisition mode (real time, triggered, programmed acquisition...)

SID4 wave front sensor is an extremely compact device which combines classical interferometry advantages (sensitivity, high resolution & dynamic range measurement) with an easy implementation.

SID4 advantages come from the 4-Wave Lateral Shearing Interferometry* (based on the Modified Hartmann Mask Diffractive Optics) an innovative technology developed at ONERA for metrology needs.

"A REVOLUTION IN WAVE FRONT SENSING"

SID4 is an essential tool for laser beam characterization and find numerous applications in optical metrology.

PHASICS - The phase control company



WAVE FRONT SENSOR

↓ SPECIFICATIONS

Wavelength Range	400 - 1100 nm
Aperture Dimension	3.6 x 4.8 mm ²
Spatial Resolution	29.6 μm
Phase and Intensity Sampling	160 x 120 (>19 000 points)
Resolution (Phase)	< 2 nm RMS
Accuracy	10 nm RMS
Dynamic range	> 100 μm
Radius of Curvature range (*)	6 mm to + ∞ (*)
Curvature resolution	< 1.10 ⁻⁹ m ⁻¹
Maximum Numerical aperture (*)	0.3 (*)
Acquisition Rate	> 100 fps
Real-time processing frequency	10 fps (full resolution)
Dimensions (WxHxL)	54 x 46 x 75.3 mm
Weight	~250 g

(*) optional software necessary

↓ SOFTWARE FEATURES

Phase map interpretation modules

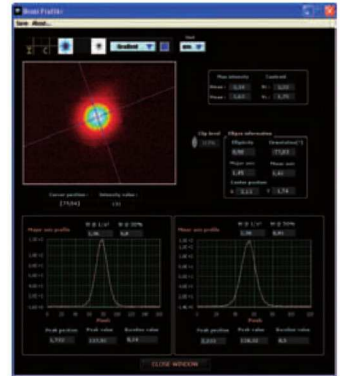
- Tilt
- Divergence
- Zernike polynomials
- Legendre polynomials

Beam analysis

- Simultaneous phase and intensity maps
- M² calculation
- Strehl ratio
- Far-field analysis



SID4 wave front sensor controlled by laptop



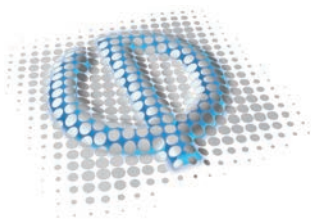
BeamView module window

Ergonomics

- Intuitive software
- Multi-user interface
- Automatic mask analysis adjustment

BeamView (option)

- Complete beam analysis
- Intensity profiles
- Gaussian fit



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